

2499-8

**International Training Workshop on FPGA Design for Scientific  
Instrumentation and Computing**

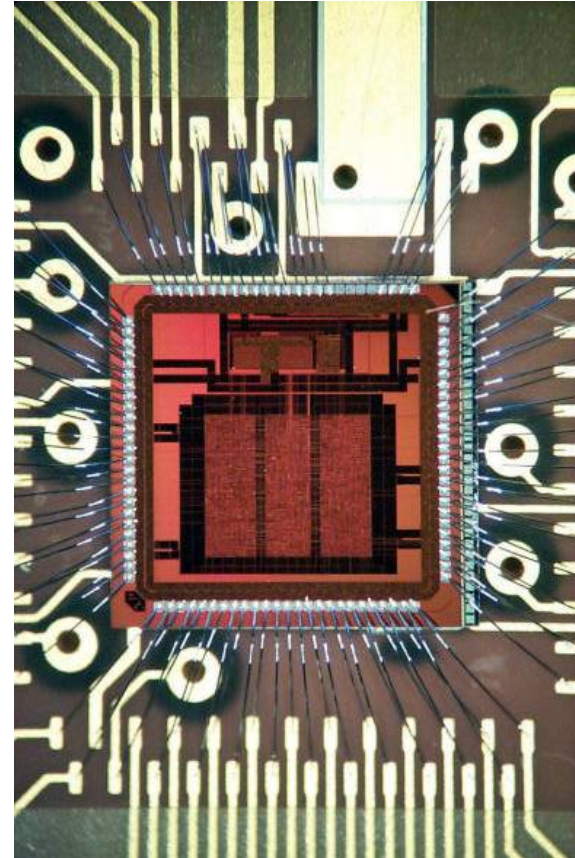
*11 - 22 November 2013*

**Introduction to VLSI Digital Design  
Gates**

Sandro BONACINI  
*CERN, Geneva  
Switzerland*

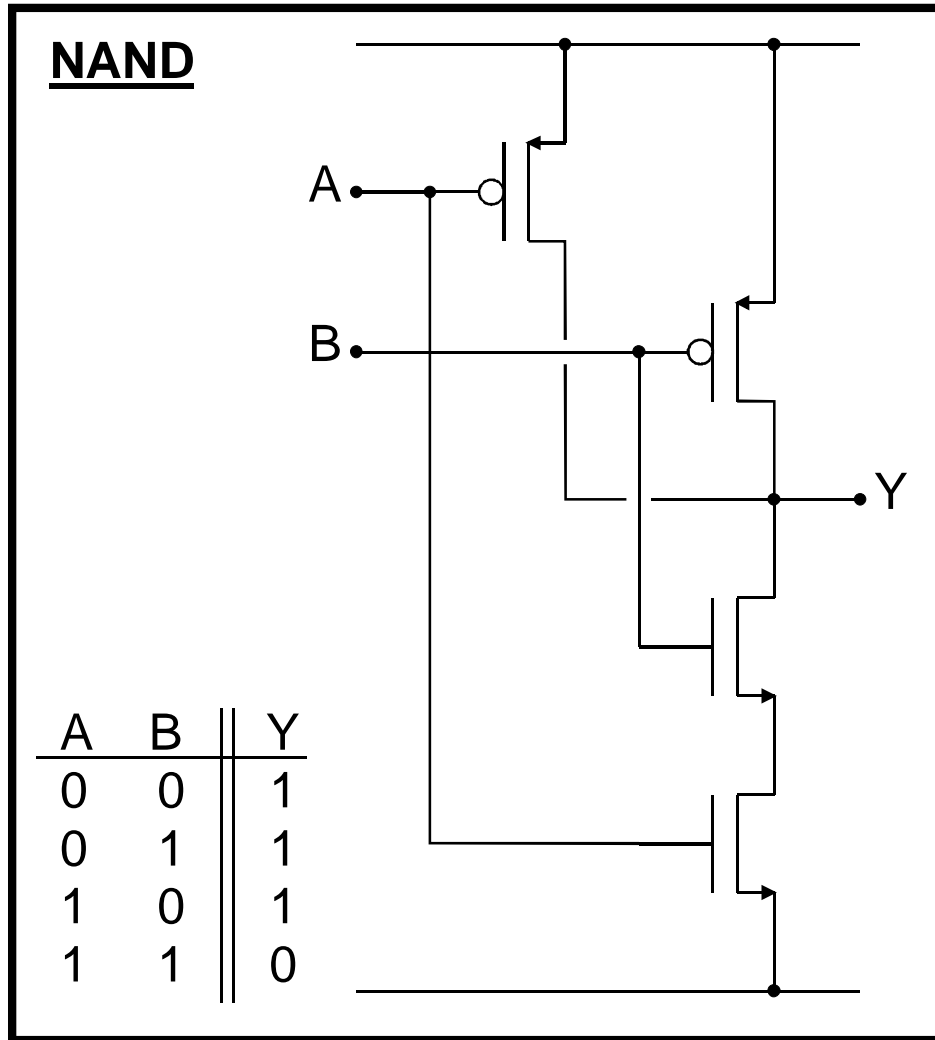
# Outline

- Introduction
- Transistors
- The CMOS inverter
- Technology
- Scaling
- **Gates**
  - The NAND gate
  - "Reading" CMOS gates
  - Designing CMOS gates
- Sequential circuits
- Storage elements
- Phase-Locked Loops
- Example



Many slides are a courtesy of Paulo Moreira

# NAND 2-inputs



"Gates are inverters in disguise!"

- Pull-down: NMOS in series
  - Need 2 NMOS "on" to pull-down
- Pull-up: PMOS in parallel
  - One PMOS "on" is sufficient to pull-up

# NAND 3-inputs

**NAND 3 inputs**

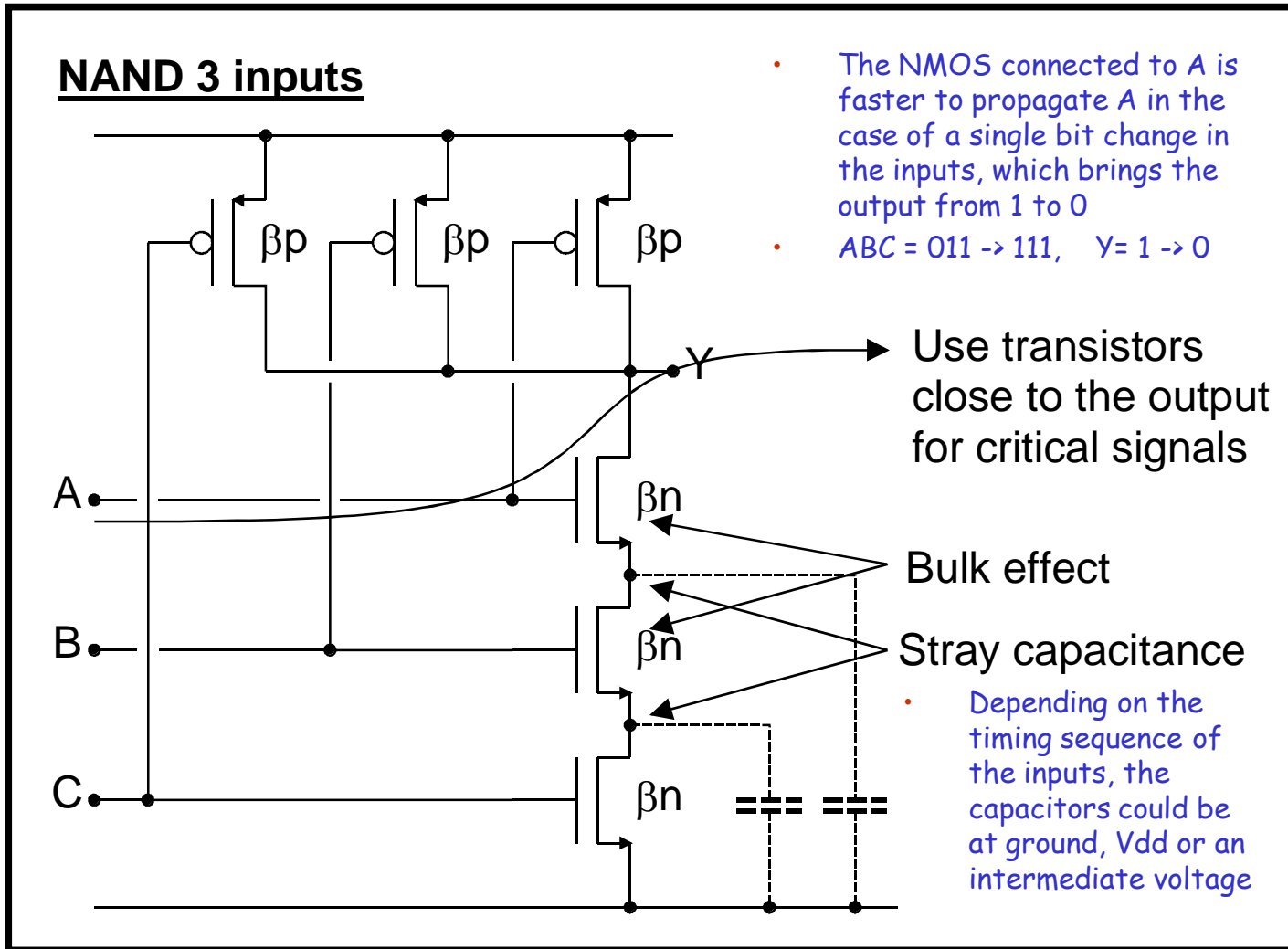
Pull down  $\Leftrightarrow 3$  on Pull up  $\Leftrightarrow 1$  on

**"Delay equivalent" inverter**

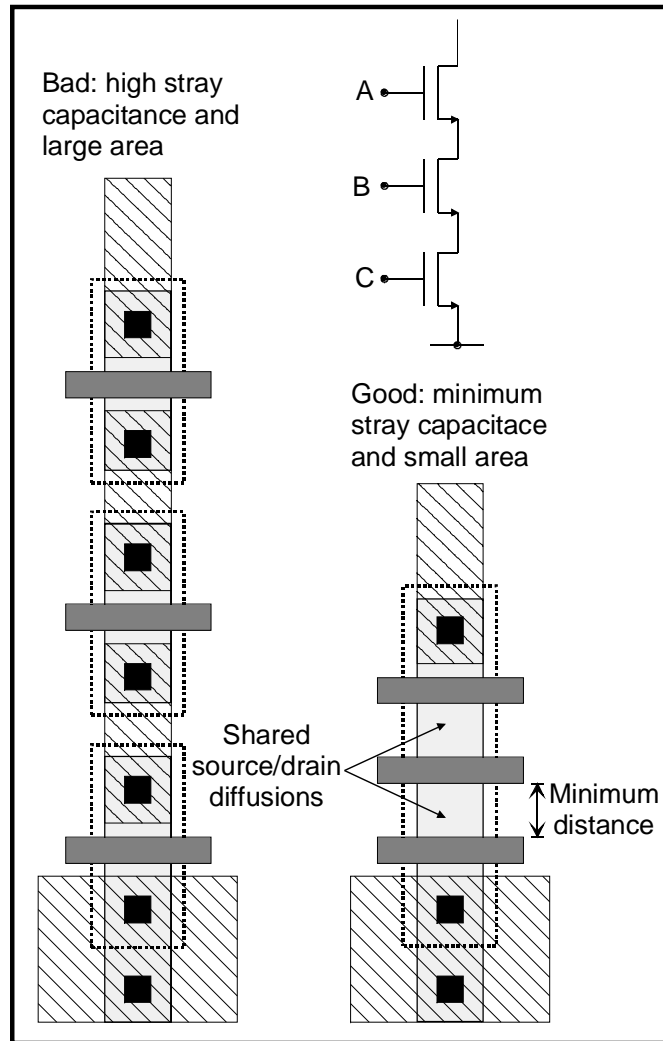
- Approximates delay

- Neglects different operating point of NMOSes:
  - $V_{gs}$ ,  $V_{ds}$ , bulk effect, "memory" of nodes

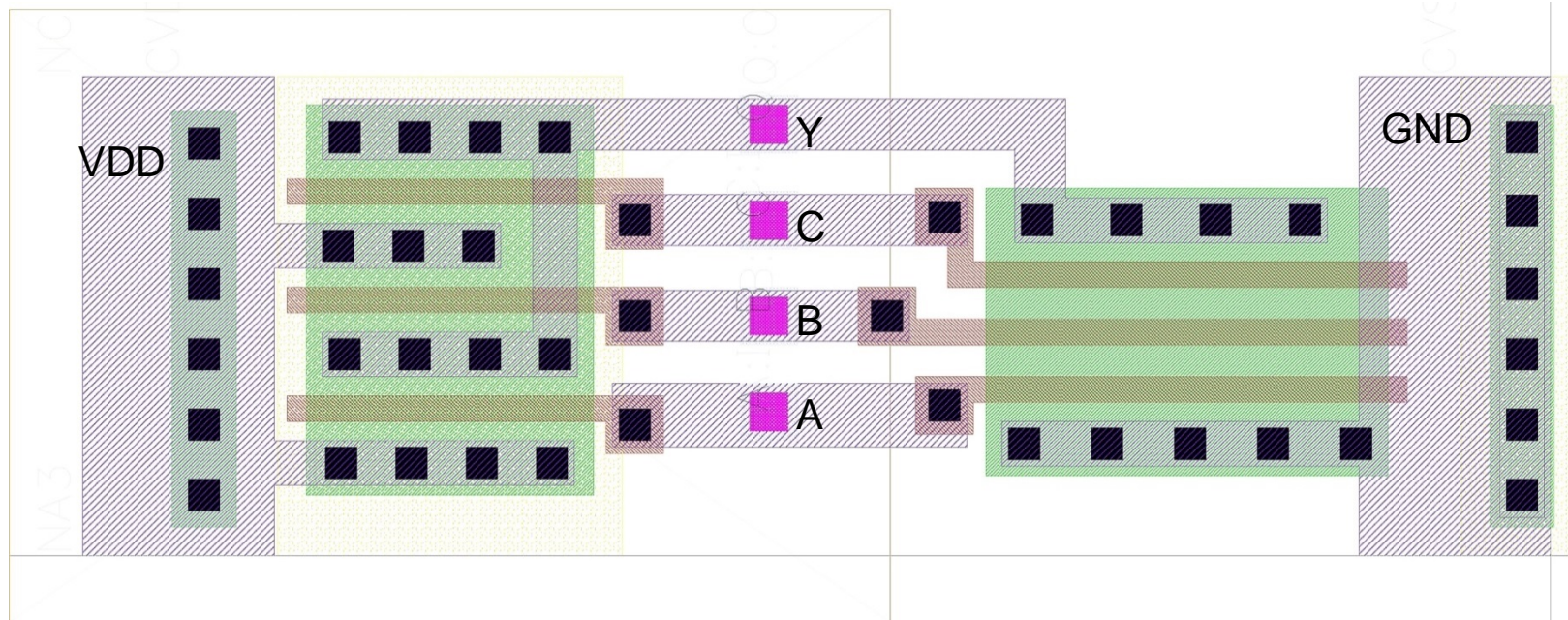
# NAND 3-inputs



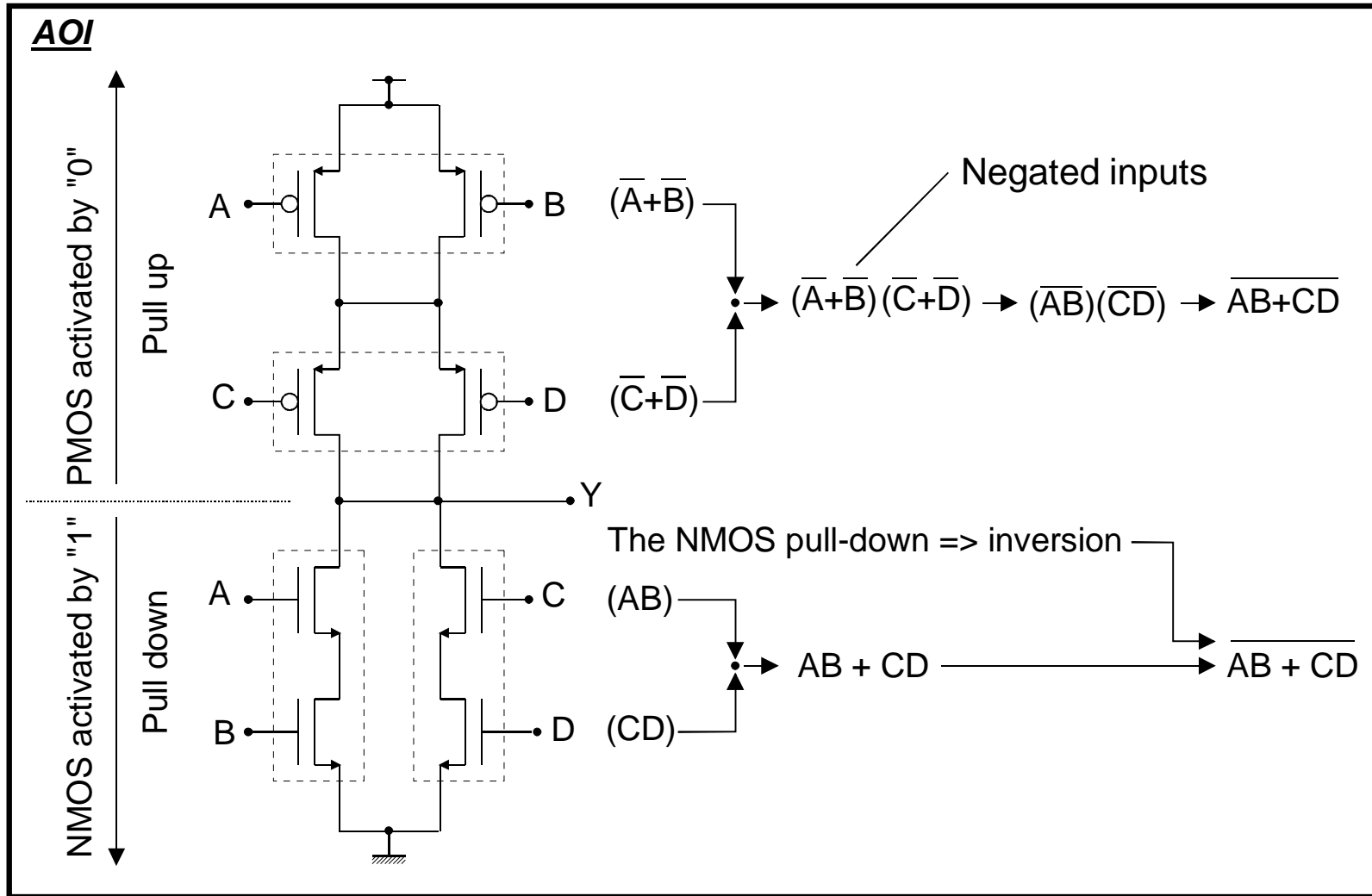
# NAND 3-inputs



# NAND 3-inputs

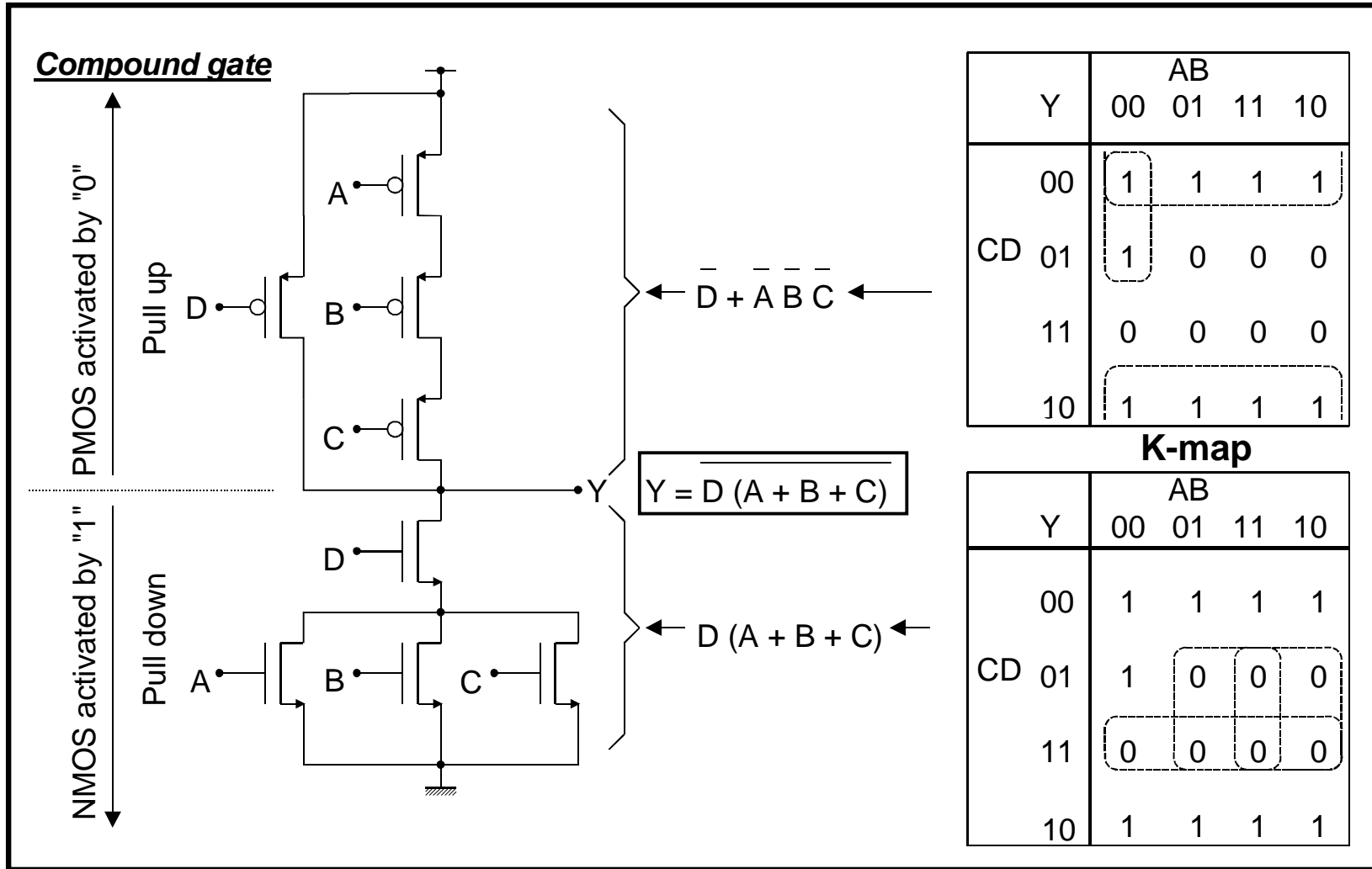


# "Reading" CMOS gates





# Designing CMOS gates



# Complex CMOS gates

---

- Can a compound gate be arbitrarily complex?

- NO, propagation delay is a strong function of fan-in:

$$t_p = a_0 \cdot FO + a_1 \cdot FI + a_2 \cdot (FI)^2$$

- FO  $\Rightarrow$  Fan-out, number of loads connected to the gate:
  - 2 gate capacitances per FO + interconnect
- FI  $\Rightarrow$  Fan-in, Number of inputs in the gate:
  - Quadratic dependency on FI due to "RC" signal path across the channels:
    - The resistance increases with the number of transistors in series
      - » E.g. (FI)  $R_o$  series NMOS for a NAND
    - Each drain and source diffusion adds additional parasitic capacitance
      - » E.g. (FI)  $C_d$  drain diffusion of PMOS for a NAND
      - »  $\rightarrow FI^2 R_o C_d$
- Avoid large FI gates (Typically  $FI \leq 4$ )